

Fujitsu LIFEBOOK® T725 Tablet PC

Environmental MIL-STD-810G

Testing Summary

P/N: FPC65-7367-01
 REV: A

Equipment tested	Fujitsu LIFEBOOK T725	
Independent test company	Quanta Laboratories, 3199 De La Cruz Boulevard, Santa Clara, CA95054 http://www.quantalabs.com/	American Association for Laboratory Accreditation: certificate #2454.01 Valid to August 31, 2016
Independent test company	ENVIRON LABORATORIES LLC, 9725 Girard Ave, South Minneapolis, MN 55431-2621 http://www.environlab.com/index.html	American Association for Laboratory Accreditation: certificate #1719.01 Valid to August 31, 2015



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Notes: All environmental testing listed in the table below was performed and reported independently by accredited testing companies listed above.

Documented MIL-STD-810G testing guidelines were followed, a summary listing of the tests are presented in the following table.

LIFEBOOK T725 Tablet PC MIL-STD-810G Testing Summary Table

#	Test Listing	Test Method	Description/Parameters	Result ^{1,2}
1	Altitude	MIL-STD-810G Method 500.5 Procedures I & II	Storage/Air Transport test at 30,000 ft, duration 1 hour, unit is non-operational Operational/Air Carriage test at 15,000 ft, duration 1 hour, unit is operational	Pass
2	Low temperature	MIL-STD-810G Method 502.5 Procedures I & II	Non-operational test at -30°C, duration 7 hours, unit is non-operational Operational test at -15°C, duration 5 hours, unit is operational	Pass
3	High temperature	MIL-STD-810G Method 501.5 Procedures I & II	Non-operational test at +70°C duration 4 hours, unit is non-operational Operational test at +60°C duration 4 hours, unit is operational	Pass
4	Functional shock	MIL-STD-810G Method 516.6 Procedure I	Non-operational test - 40G, 11 ms, saw-tooth pulse configuration, 3 shocks, ± per axis, unit is non-operational Operational test - 20G, 11 ms, saw-tooth pulse configuration, 3 shocks, ± per axis, unit is operational	Pass
5	Vibration, integrity	MIL-STD-810G Method 514.6 Category 24	Non-operational test, Minimum integrity test 20-2000Hz; 20-1000 Hz at 0.04G ² /Hz, 1000 2000Hz at 6dB, overall 7.7G RMS; test profile see in figure 514.6E-1. Test duration: 1 hours x 3 axis. Unit is non-operational	Pass
6	Vehicle Vibration	MIL-STD-810G Method 514.6 Category 20	Operational test - Ground vehicle, US Highways 1,000 miles of transportation, test profile see figure 514.6C-I and table 514.6C-II. Test duration: 1 hours x 3 axis. Unit is operational.	Pass
7	Blowing Dust	MIL-STD-810G Method 510.5 Procedure I	Non-operational test duration 6 hours, dust density 10±7 g/m ³ , air velocity 8.9m/s, 140 mesh silica flower at 25°C ambient. Unit is non-operational Operational test duration 6 hours, dust density 10±7 g/m ³ , air velocity 8.9m/s, 140 mesh silica flower at 35°C ambient. Unit is operational	Pass
8	Transit Drop	MIL-STD-810G Method 516.6	Non-operational test, transit drop from 30" height on 2" plywood. One drop each on 4 corners, 8 edges, 6 faces. Unit is closed and non-operational.	Refer footnote*

¹Pass for Operational test indicates that unit remained operational during the entirety of the test. After the test ran and verified one complete pass of Fujitsu proprietary diagnostic software.

²Pass for Non-operational test indicates that after the test unit powered, booted to Windows OS, ran and verified one complete pass of Fujitsu proprietary diagnostic software.

*Test units passed functional performance test after each drop and remained operational after all tests were completed. Some mechanical damage was observed.

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